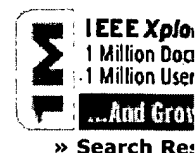




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Pages:326 - 332

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4 The use of unified APC/FD in the control of a metal etch area*Hyde, J.; Doxsey, J.; Card, J.;*

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5 Advanced analysis of dynamic neural control advisories for process optimization and parts maintenance*Card, J.P.; Chan, W.T.; Cao, A.; Martin, W.; Morgan, J.;*

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2 Algorithmic fusion of gene expression profiling for diffuse large B-cell lymphoma outcome prediction

Qiuming Zhu; Hongmei Cui; Kajia Cao; Chan, W.C.;

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3 Linearization of receivers using envelope signal injection

Chan, W.H.Y.; Bock, G.;

Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave Letters] , Volume: 14 , Issue: 7 , July 2004

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[\[Abstract\]](#) [\[PDF Full-Text \(160KB\)\]](#) **IEEE JNL**

4 Linearization of mixers using predistortion and envelope signal injection

Chan, W.H.Y.; Bock, G.;

Microwave and Wireless Components Letters, IEEE [see also IEEE Microwave and Guided Wave Letters] , Volume: 14 , Issue: 3 , March 2004

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5 Interconnected linear multivariable systems with delays: System properties and input-output stability

Desoer, C.; Chan, W.;

Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977

Pages:604 - 610

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6 Robustness of stability conditions for linear time-invariant feedback systems

Desoer, C.; Callier, F.; Chan, W.;

Automatic Control, IEEE Transactions on , Volume: 22 , Issue: 4 , Aug 1977
Pages:586 - 590

[\[Abstract\]](#) [\[PDF Full-Text \(584KB\)\]](#) IEEE JNL

7 A basis for the controllable canonical form of linear time-invariant multiinput systems

Chan, W.; Wang, Y.;

Automatic Control, IEEE Transactions on , Volume: 23 , Issue: 4 , Aug 1978
Pages:742 - 745

[\[Abstract\]](#) [\[PDF Full-Text \(304KB\)\]](#) IEEE JNL

8 Eigenvalue assignment and stabilization of interconnected systems using local feedbacks

Chan, W.; Desoer, C.;

Automatic Control, IEEE Transactions on , Volume: 24 , Issue: 2 , Apr 1979
Pages:312 - 317

[\[Abstract\]](#) [\[PDF Full-Text \(488KB\)\]](#) IEEE JNL

9 Measurement of Nonplanar Dielectric Samples Using an Open Resonator

Chan, W.F.P.; Chambers, B.;

Microwave Theory and Techniques, IEEE Transactions on , Volume: 35 , Issue: 12 , Dec 1987
Pages:1429 - 1434

[\[Abstract\]](#) [\[PDF Full-Text \(752KB\)\]](#) IEEE JNL

10 A SFH spread spectrum synchronization algorithm for data broadcasting

Siu, Y.M.; Chan, W.S.; Leung, S.W.;

Broadcasting, IEEE Transactions on , Volume: 47 , Issue: 1 , March 2001
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[\[Abstract\]](#) [\[PDF Full-Text \(96KB\)\]](#) IEEE JNL

11 Optimizing symbolic model checking for statecharts

Chan, W.; Anderson, R.J.; Beame, P.; Jones, D.H.; Notkin, D.; Warner, W.E.;

Software Engineering, IEEE Transactions on , Volume: 27 , Issue: 2 , Feb. 2001
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[\[Abstract\]](#) [\[PDF Full-Text \(508KB\)\]](#) IEEE JNL

12 Rapid and accurate inter-robot position determination in robot teams

Jason Wu; Chan, W.K.; Thomas, G.;

Instrumentation and Measurement, IEEE Transactions on , Volume: 50 , Issue: 1 , Feb. 2001
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[\[Abstract\]](#) [\[PDF Full-Text \(100KB\)\]](#) IEEE JNL

13 A novel compact PMSM with magnetic bearing for artificial heart application

Shen, J.X.; Tseng, K.J.; Vilathgamuwa, D.M.; Chan, W.K.;
Industry Applications, IEEE Transactions on ,Volume: 36 , Issue: 4 , July-Aug.
2000
Pages:1061 - 1068

[\[Abstract\]](#) [\[PDF Full-Text \(612KB\)\]](#) IEEE JNL

14 Internet based transmission substation monitoring

Chan, W.L.; So, A.T.P.; Lai, L.L.;
Power Systems, IEEE Transactions on ,Volume: 14 , Issue: 1 , Feb. 1999
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[\[Abstract\]](#) [\[PDF Full-Text \(1188KB\)\]](#) IEEE JNL

15 Real-time frequency and harmonic evaluation using artificial neural networks

Lai, L.L.; Chan, W.L.; Tse, C.T.; So, A.T.P.;
Power Delivery, IEEE Transactions on ,Volume: 14 , Issue: 1 , Jan. 1999
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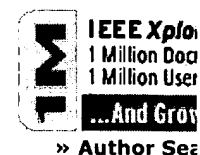
Industrial Automation and Control: Emerging Technologies, 1995., International IEEE/IAS Conference on , 22-27 May 1995

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 Software Reliability Engineering, 1993. Proceedings., Fourth International Symposium on , 3-6 Nov. 1993

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Yang, M.C.; Cienkus, M.; Hajovsky, M.; Basey, T.;

Thermal and Thermomechanical Phenomena in Electronic Systems, 2000. ITherm 2000. The Seventh Intersociety Conference on , Volume: 2 , 23-26 May 2000
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15 Irradiation experiments with high-voltage power devices as a possible means to predict failure rates due to cosmic rays

Voss, P.; Maier, K.H.; Meczynski, W.; Becker, H.W.; Normand, E.; Wert, J.L.;
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Power Semiconductor Devices and IC's, 1997. ISPSD '97., 1997 IEEE International Symposium on , 26-29 May 1997
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 Software Reliability Engineering, 1993. Proceedings., Fourth International Symposium on , 3-6 Nov. 1993

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[\[Abstract\]](#) [\[PDF Full-Text \(1120 KB\)\]](#) IEEE CNF

14 A method to predict failure of solder joints caused by thermal shock using finite element analysis for RF power amplifier applications

Yang, M.C.; Cienkus, M.; Hajovsky, M.; Basey, T.;

Thermal and Thermomechanical Phenomena in Electronic Systems, 2000. ITherm 2000. The Seventh Intersociety Conference on , Volume: 2 , 23-26 May 2000
Pages:169 - 173 vol. 2

[\[Abstract\]](#) [\[PDF Full-Text \(280 KB\)\]](#) IEEE CNF

15 Irradiation experiments with high-voltage power devices as a possible means to predict failure rates due to cosmic rays

Voss, P.; Maier, K.H.; Meczynski, W.; Becker, H.W.; Normand, E.; Wert, J.L.;

Oberg, D.I.; Majewski, P.P.;

Power Semiconductor Devices and IC's, 1997. ISPSD '97., 1997 IEEE International Symposium on , 26-29 May 1997
Pages:169 - 172

[\[Abstract\]](#) [\[PDF Full-Text \(420 KB\)\]](#) IEEE CNF

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